

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

APPLICANTS : Jong-Cheol Lee, et al. **ATTY DOCKET NO.** : 8836-223 (ID12244-US)
SERIAL NO. : 10/748,906 **EXAMINER** : Saqib Javaid Siddiqui
FILED : December 30, 2003 **ART UNIT** : 2138
TITLE : *SEMICONDUCTOR MEMORY DEVICE TESTABLE WITH A SINGLE DATA RATE AND/OR
DUAL DATA RATE PATTERN IN A MERGED DATA INPUT/OUTPUT PIN TEST MODE*

MAIL STOP: AMENDMENT

Commissioner for Patents

P.O. Box 1450

Alexandria, VA 22313-1450

AMENDMENT

S I R :

In response to the Official Action of November 24, 2006, applicants respectfully request that the above-identified application be amended as follows.

Amendments to the claims are reflected in the Listing of Claims that begins on page 2 of this Amendment.

Amendments to the drawings are set forth on page 6 of this Amendment and include a replacement sheet for FIG. 1.

The Remarks portion begins on page 7 of this Amendment.